

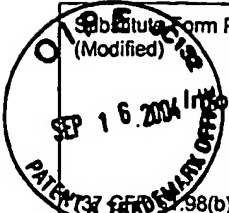
Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 16785-007001	Application No. 10/763,682
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant Randy Beeman et al.	
		Filing Date January 23, 2004	Group Art Unit

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>E</i>	AA	6,357,892	March 2002	Beadle	<del>          </del>		
<i>2</i>	AB	6,608,614	August 2003	Johnson	<del>          </del>		
<i>2</i>	AC	US2002/0001192A1	January 2002	Suchiro et al.	<del>          </del>		
<i>2</i>	AD	US2003/0161110A1	August 2003	Spasevski et al.	<del>          </del>		
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature <i>David W</i>	Date Considered <i>6/6/06</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>D</i>	AA	6,166,496	12/26/2000	Lys et al.			
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